BLF6G13L-250P; BLF6G13LS-250P

Power LDMOS transistor

Rev. 3 — 14 October 2011 Product data sheet

1. Product profile

1.1 General description

250 W LDMOS power transistor intended for CW applications at a frequency of 1.3 GHz.

Table 1. Test information

Typical RF performance at T_{case} = 25 °C; I_{Dq} = 100 mA; in a class-AB production test circuit.

Mode of operation	f (GHz)	V_{DS} (V)	$P_{L(1dB)}$ (W)	G_p (dB)	η_D (%)
CW	1.3	50	250	17	56

1.2 Features and benefits

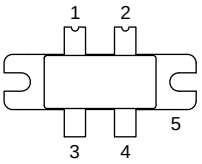
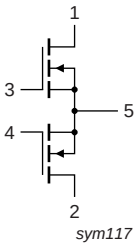
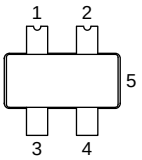
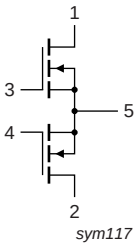
- Typical CW performance at a frequency of 1.3 GHz, a supply voltage of 50 V, an I_{Dq} of 100 mA:
  - Output power = 250 W
  - Power gain = 17 dB
  - Efficiency = 56 %
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Internally matched for ease of use
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

- Industrial, scientific and medical applications

2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
BLF6G13L-250P (SOT1121A)			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source [1]		
BLF6G13LS-250P (SOT1121B)			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source [1]		

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BLF6G13L-250P	-	flanged LDMOST ceramic package; 2 mounting holes; 4 leads	SOT1121A
BLF6G13LS-250P	-	earless flanged LDMOST ceramic package; 4 leads	SOT1121B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	100	V
V_{GS}	gate-source voltage		–0.5	+13	V
I_D	drain current		-	42	A
T_{stg}	storage temperature		–65	+150	°C
T_j	junction temperature		-	200	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	T_{case} = 85 °C; P_L = 250 W	0.26	K/W

6. Characteristics

Table 6. DC characteristics

T_j = 25 °C; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	V_{GS} = 0 V; I_D = 1.4 mA	100	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	V_{DS} = 10 V; I_D = 235 mA	1.4	1.8	2.4	V
I_{DSS}	drain leakage current	V_{GS} = 0 V; V_{DS} = 50 V	-	-	1.4	μA
I_{DSX}	drain cut-off current	V_{GS} = $V_{GS(th)}$ + 3.75 V; V_{DS} = 10 V	-	21	-	A
I_{GSS}	gate leakage current	V_{GS} = 11 V; V_{DS} = 0 V	-	-	240	nA
g_{fs}	forward transconductance	V_{DS} = 10 V; I_D = 120 mA	-	1	-	S
$R_{DS(on)}$	drain-source on-state resistance	V_{GS} = $V_{GS(th)}$ + 3.75 V; I_D = 4.75 A	-	200	-	mΩ

Table 7. RF characteristics

Mode of operation: CW; f = 1.3 GHz; RF performance at V_{DS} = 50 V; I_{Dq} = 100 mA; T_{case} = 25 °C; unless otherwise specified, in a class-AB production test circuit.

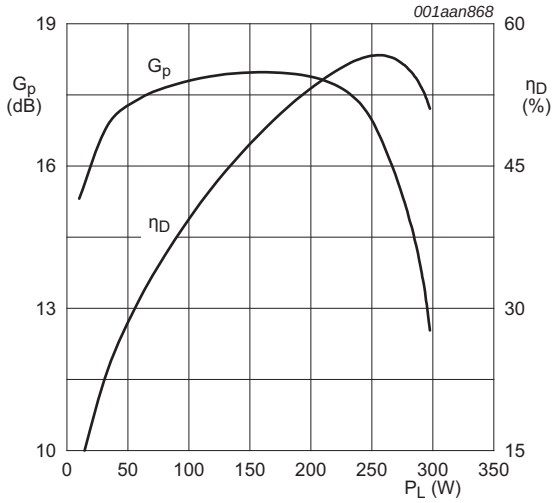
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
P_L	output power		250	-	-	W
V_{DS}	drain-source voltage	P_L = 250 W	-	-	50	V
G_p	power gain	P_L = 250 W	15	17	-	dB
RL_{in}	input return loss	P_L = 250 W	-	–30	–20	dB
η_D	drain efficiency	P_L = 250 W	52	56	-	%

6.1 Ruggedness in class-AB operation

The BLF6G13L-250P and BLF6G13LS-250P are capable of withstanding a load mismatch corresponding to VSWR = 5 : 1 through all phases under the following conditions: V_{DS} = 50 V; I_{Dq} = 100 mA; P_L = 250 W; f = 1.3 GHz.

7. Application information

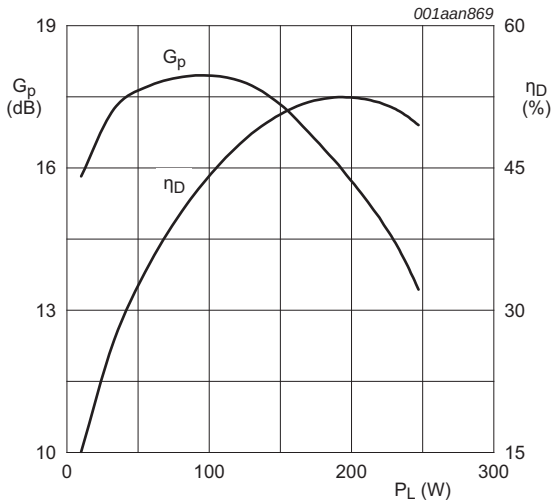
7.1 CW



V_{DS} = 50 V; I_{Dq} = 100 mA.

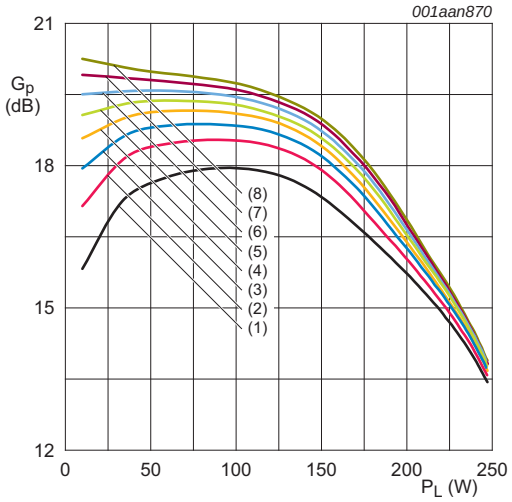
Fig 1. Power gain and drain efficiency as function of load power; typical values

7.2 2-Carrier CW



V_{DS} = 50 V; I_{Dq} = 100 mA; carrier spacing = 100 kHz.

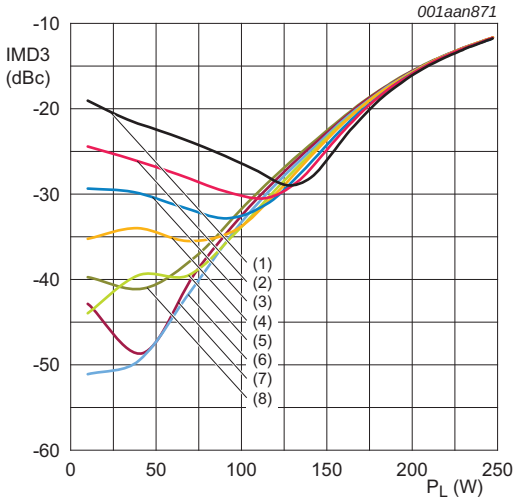
Fig 2. Power gain and drain efficiency as function of load power; typical values



V_{DS} = 50 V; f = 1300 MHz; carrier spacing = 100 kHz.

(1) I_{Dq} = 100 mA
(2) I_{Dq} = 300 mA
(3) I_{Dq} = 500 mA
(4) I_{Dq} = 700 mA
(5) I_{Dq} = 900 mA
(6) I_{Dq} = 1100 mA
(7) I_{Dq} = 1300 mA
(8) I_{Dq} = 1500 mA

Fig 3. Power gain as a function of load power; typical values



V_{DS} = 50 V; f = 1300 MHz; carrier spacing = 100 kHz.

(1) I_{Dq} = 100 mA
(2) I_{Dq} = 300 mA
(3) I_{Dq} = 500 mA
(4) I_{Dq} = 700 mA
(5) I_{Dq} = 900 mA
(6) I_{Dq} = 1100 mA
(7) I_{Dq} = 1300 mA
(8) I_{Dq} = 1500 mA

Fig 4. Third order intermodulation distortion as a function of load power; typical values

7.3 Impedance information

Table 8. Typical impedance

Typical values valid per section unless otherwise specified.

f	Z_S	Z_L optimized for G_p	Z_L optimized for η_D
MHz	Ω	Ω	Ω
1200	3.03 – j8.15	2.03 – j0.25	1.46 – j0.47
1300	4.06 – j9.52	1.67 – j0.92	1.19 – j0.95
1400	7.00 – j9.61	1.50 – j1.48	1.22 – j1.49

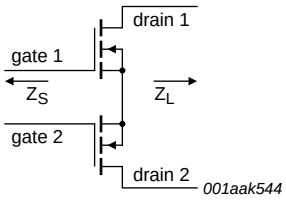


Fig 5. Definition of transistor impedance

7.4 Circuit information

Table 9. List of components

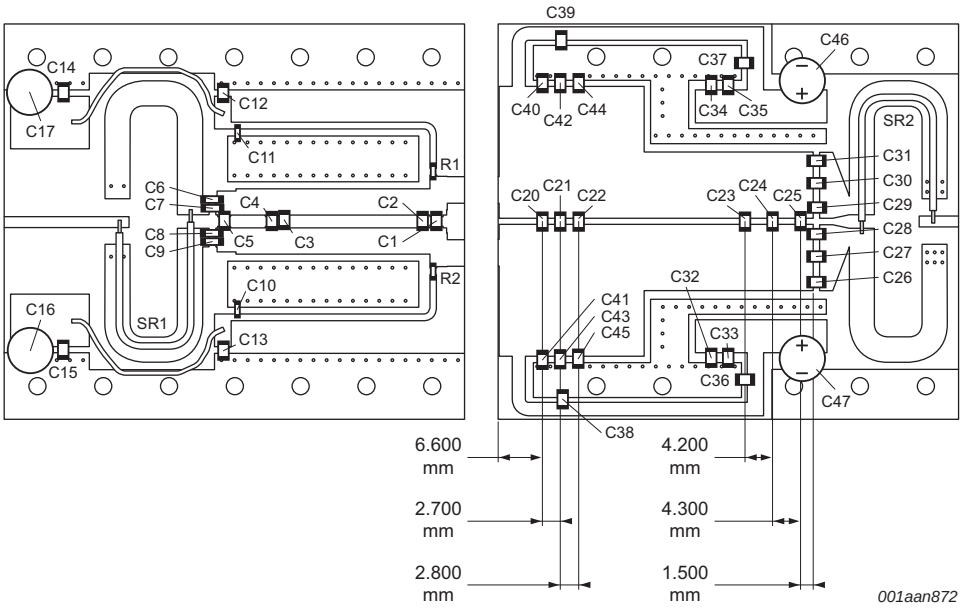
For application circuit see Figure 6.

Component	Description	Value		Remarks
C1, C2	multilayer ceramic chip capacitor	1.9 pF	[1]	
C3, C4	multilayer ceramic chip capacitor	4.7 pF	[1]	
C5	multilayer ceramic chip capacitor	10 pF	[1]	
C6, C7, C8, C9, C10, C11, C38, C39	multilayer ceramic chip capacitor	56 pF	[1]	
C12, C13	multilayer ceramic chip capacitor	100 pF	[2]	
C14, C15, C32, C34	multilayer ceramic chip capacitor	1 nF	[2]	
C16, C17	electrolytic capacitor	10 μF; 50 V		220 X5R
C20, C21, C22, C23	multilayer ceramic chip capacitor	3.0 pF	[1]	
C40, C41	multilayer ceramic chip capacitor	2.4 pF	[1]	
C42, C43, C44, C45	multilayer ceramic chip capacitor	2.7 pF	[1]	
C24	multilayer ceramic chip capacitor	0.8 pF	[1]	
C25	multilayer ceramic chip capacitor	0.6 pF	[1]	
C26, C27, c28, C29, C30, C31, C33, C35	multilayer ceramic chip capacitor	100 pF	[1]	
C36, C37	multilayer ceramic chip capacitor	20 nF	[3]	
C46, C47	electrolytic capacitor	100 μF; 63 V		
R1, R2	SMD resistor 0603	5.1 Ω		UT-141C-25-TP
SR1	COAX	25 Ω		UT-141C-35-TP
SR2	COAX	35 Ω		

[1] American Technical Ceramics type 800B or capacitor of same quality.

[2] American Technical Ceramics type 100B or capacitor of same quality.

[3] American Technical Ceramics type 200B or capacitor of same quality.



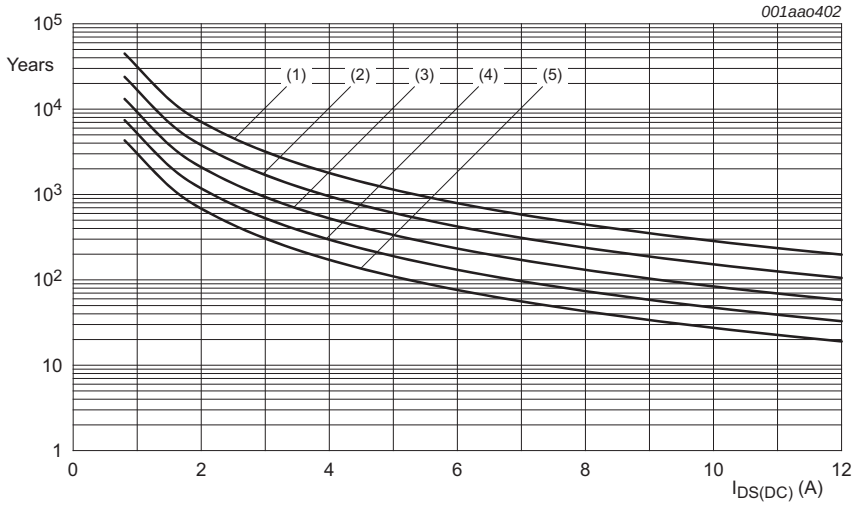
Printed-Circuit Board (PCB): Duroid 4350B; ε_r = 3.48; thickness = 0.762 mm; thickness copper plating = 35 μm.

See Table 9 for a list of components.

Fig 6. Component layout for application circuit

8. Test information

8.1 Reliability



MTTF (Years)

The reliability at pulsed conditions can be calculated as follows: MTTF x 1 / δ.

(1) T_j = 130 °C

(2) T_j = 140 °C

(3) T_j = 150 °C

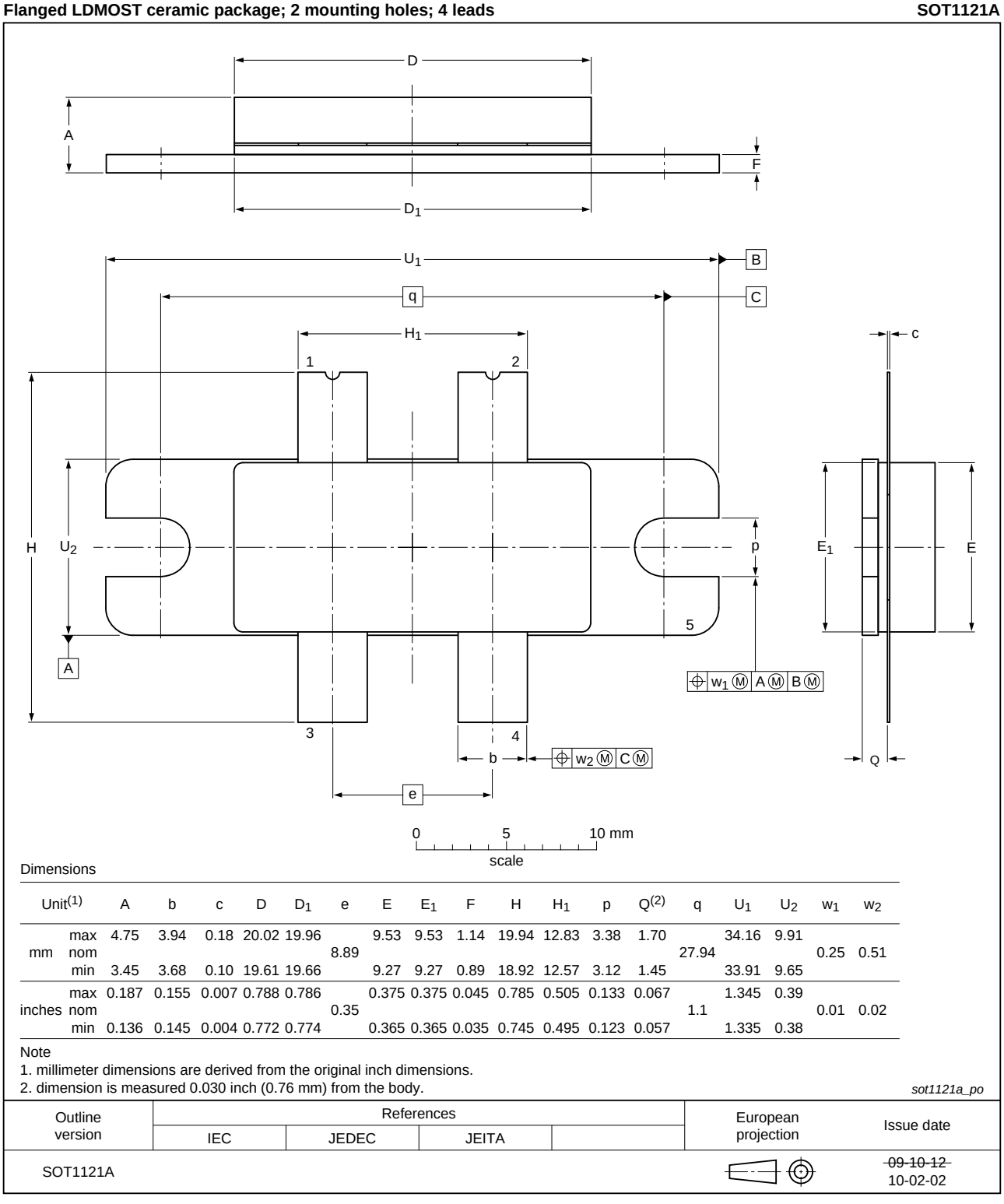
(4) T_j = 160 °C

(5) T_j = 170 °C

Fig 7. Electromigration ($I_{DS(DC)}$, total device)

9. Package outline

Flanged LDMOST ceramic package; 2 mounting holes; 4 leads **SOT1121A**



Dimensions

Unit[1]		A	b	c	D	D1	e	E	E1	F	H	H1	p	Q[2]	q	U1	U2	w1	w2
mm	max	4.75	3.94	0.18	20.02	19.96		9.53	9.53	1.14	19.94	12.83	3.38	1.70		34.16	9.91		
	nom						8.89								27.94			0.25	0.51
	min	3.45	3.68	0.10	19.61	19.66		9.27	9.27	0.89	18.92	12.57	3.12	1.45		33.91	9.65		
inches	max	0.187	0.155	0.007	0.788	0.786		0.375	0.375	0.045	0.785	0.505	0.133	0.067		1.345	0.39		
	nom						0.35								1.1			0.01	0.02
	min	0.136	0.145	0.004	0.772	0.774		0.365	0.365	0.035	0.745	0.495	0.123	0.057		1.335	0.38		

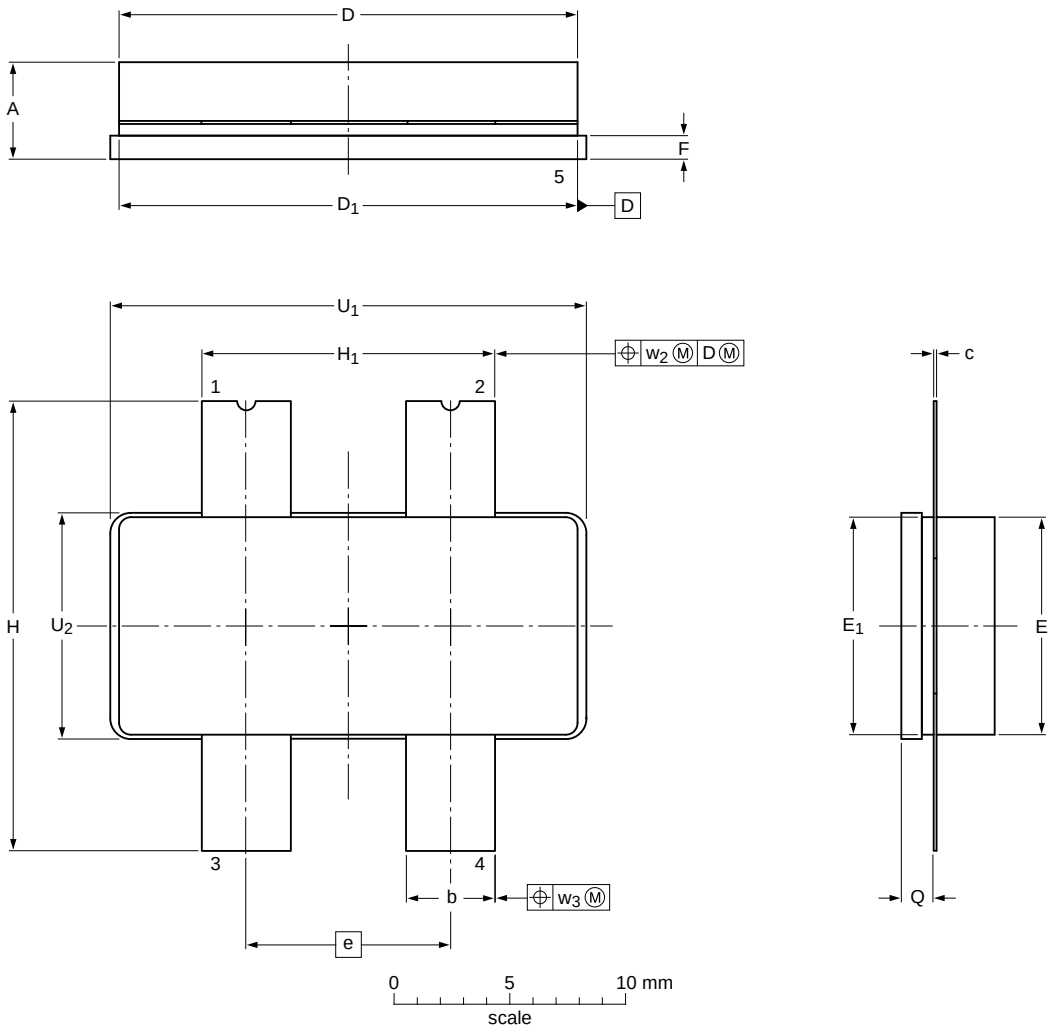
Note
1. millimeter dimensions are derived from the original inch dimensions.
2. dimension is measured 0.030 inch (0.76 mm) from the body.

sot1121a_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
SOT1121A						~~09-10-12~~ 10-02-02

Fig 8. Package outline SOT1121A

Earless flanged LDMOST ceramic package; 4 leads **SOT1121B**



Dimensions

Unit[1]		A	b	c	D	D_1	e	E	E_1	F	H	H_1	Q	U_1	U_2	w_2	w_3
mm	max	4.75	3.94	0.18	20.02	19.96		9.53	9.53	1.14	19.94	12.83	1.70	20.70	9.91		
	nom						8.89									0.51	0.25
	min	3.45	3.68	0.08	19.61	19.66		9.27	9.27	0.89	18.92	12.57	1.45	20.45	9.65		
inches	max	0.187	0.155	0.007	0.788	0.786		0.375	0.375	0.045	0.785	0.505	0.067	0.815	0.39		
	nom						0.35									0.02	0.01
	min	0.136	0.145	0.003	0.772	0.774		0.365	0.365	0.035	0.745	0.495	0.057	0.805	0.38		

Note

1. millimeter dimensions are derived from the original inch dimensions.
2. dimension is measured 0.030 inch (0.76 mm) from the body.

sot1121b_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
SOT1121B						~~09-10-12~~ 09-12-14

Fig 9. Package outline SOT1121B

10. Handling information

CAUTION

This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

11. Abbreviations

Table 10. Abbreviations

Acronym	Description
CW	Continuous Wave
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
MTTF	Mean Time To Failure
RF	Radio Frequency
SMD	Surface Mount Device
VSWR	Voltage Standing-Wave Ratio

12. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF6G13L-250P_6G13LS-250P v.3	20111014	Product data sheet	-	BLF6G13L-250P_6G13LS-250P v.2
Modifications:	• Table 6 on page 3: Several values have been updated • Table 7 on page 3: The minimum value for η_D has been updated • Section 8.1 on page 8: This section has been added			
BLF6G13L-250P_6G13LS-250P v.2	20110321	Objective data sheet	-	BLF6G13L-250P_6G13LS-250P v.1
BLF6G13L-250P_6G13LS-250P v.1	20101102	Objective data sheet	-	-

13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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15. Contents

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